

**Notice of References Cited**

Application/Control No.

10/530,704

Applicant(s)/Patent Under  
Reexamination  
WU, WEI

Examiner

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Art Unit

2858

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	Silvester, Peter, Finite Elements for Electrical Engineers, Cambridge University Press, 1996, p. 10-15, 112-117
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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